

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/685,473	KLEIN, MARTIN G.
Examiner	Art Unit	
Dah-Wei D. Yuan	1745	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
429	122	2/22/2007	DWY
429	128	2/22/2007	DWY
429	142	2/22/2007	DWY